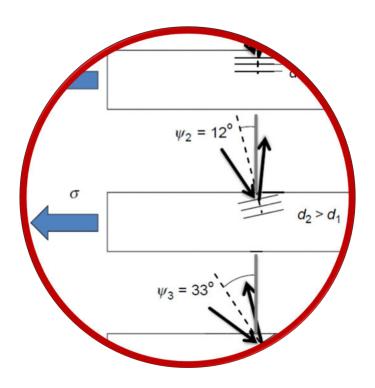
Disclaimer

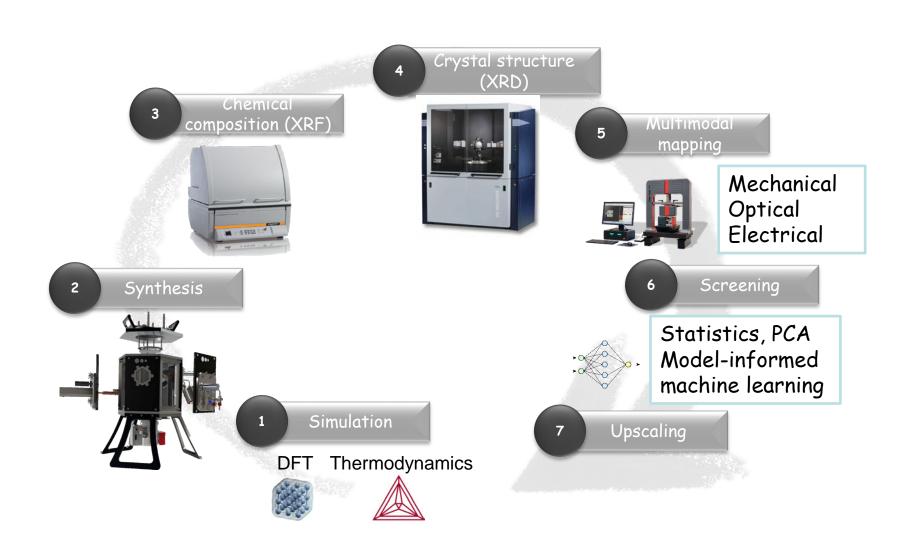
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Ch. 7: Outlook

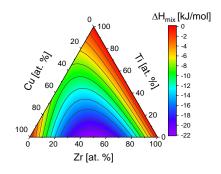


Outlook: Accelerated materials discovery through combinatorial thin film libaries

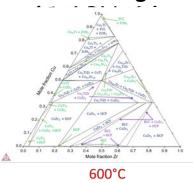


Simulation - preselection of elements

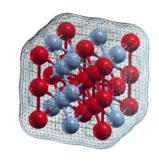
Empirical rules

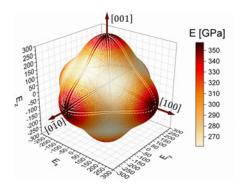


Thermodynamical modelling

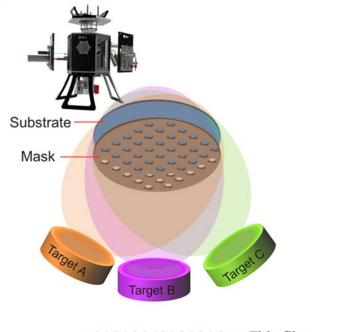


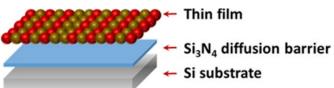
Density functional theory





Deposition - combinatorial thin film libraries

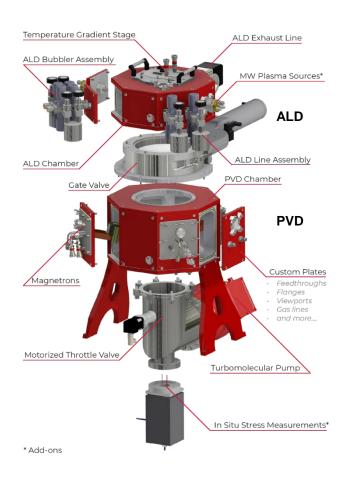






- 4in wafer with 69 patches
- Si₃N₄ interlayer for diffusion barrier, chemical inertness, electrical isolation
- Composition gradient: ±20at%

Deposition - novel equipment

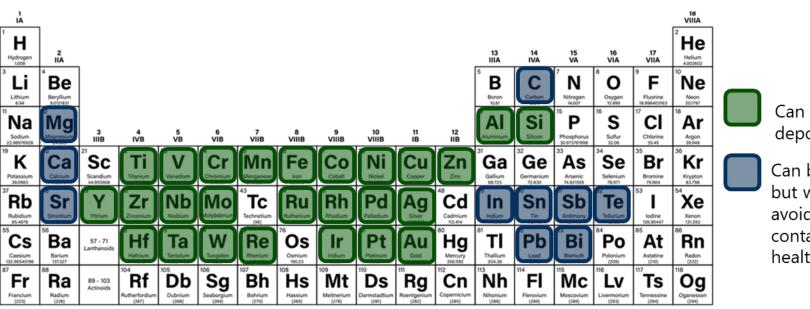






- Laboratory cluster system
 - combines PVD and ALD
- Up to 8 magnetrons
- Temperature gradient stage (RT to 400°C)
- HIPIMS compatible
- 4 inch wafer substrates

PVD possible targets



Can be deposited

Can be deposited, but we prefer to avoid (chamber contamination or health concerns)

La Lanthanum 138.90547	Cerium	Praseodymium	Neodymium	Pm Promethium (145)	Sm Samarium 150.36	Europium	Gd Gadolinium	7b Terbium 158.92535	Dy Dysprosium 162,500	Ho Holmium 164,93033	Erbium	Tm Thulium 168.93422	Yb Ytterbium 173,045	Lu Lutetium 174,9668
Ac Actions	Th	Protectioium	U Uranium	Np Necturium	Pu Plutonium	American	°Cm	Bk Berkelium	°Cf	Es Finsteinium	Femium	Md	No No	Lr Lr



Composition mapping

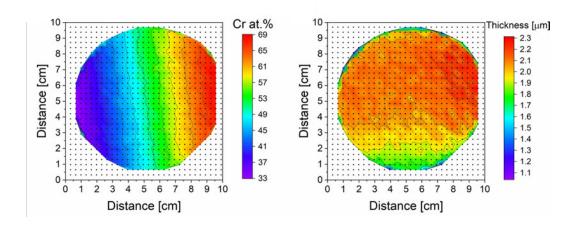


Fischerscope X-Ray XDV-SDD

XRF mapping on each patch:

- Chemical composition
- Coating thickness





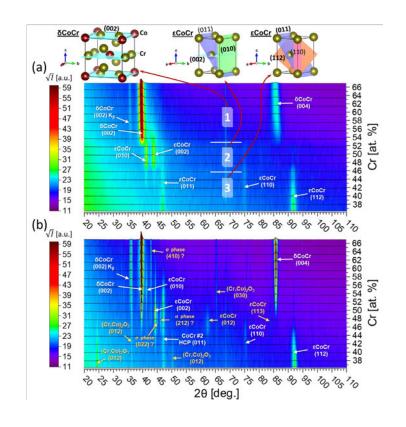
Microstructure mapping



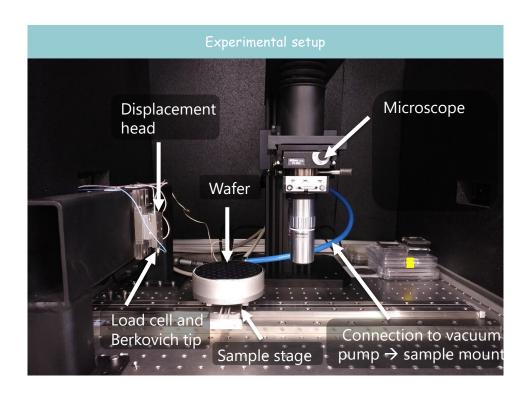


XRD mapping on each patch:

- Identification of phases
- Grain size analysis
- Correlation with composition

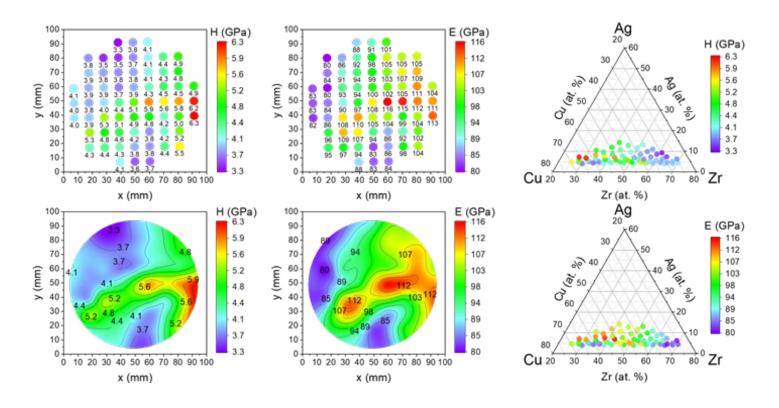


Mechanical property mapping



- High accuracy, low noise for thin film mechanical property measurements
- Automatic mapping of mechanical properties on 4in wafers
- Constant machine compliance
 - Guarantees consistent results over whole wafer
- Nanoindentation for measuring hardness, modulus, coating adhesion
- Scratch testing

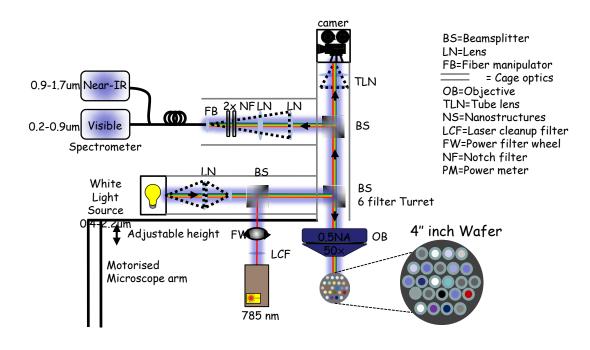
Mechanical property mapping - CuZrAg



Hardness and modulus correlated to composition

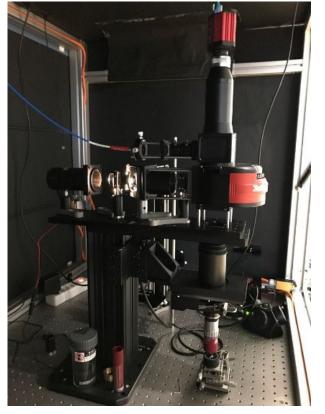


Optical property mapping



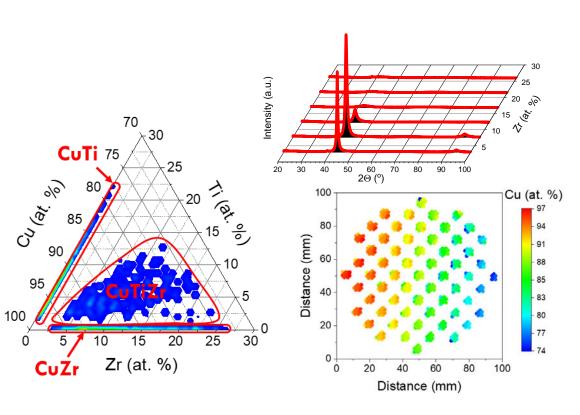


Raman spectroscopy (785nm laser)



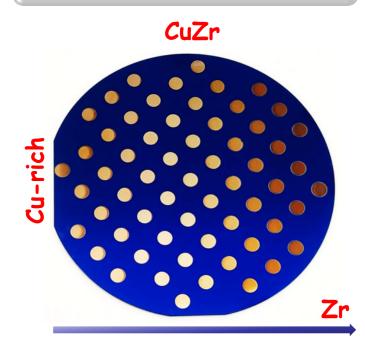


Optical property mapping - CuZrTi



Note: Colour of the thin film changes significantly with the gradient of the chemical composition

Heat treatment: 200°C / 10 min Atmosphere: air





Combinatorial materials discovery - outline

